



UNITED STATES PATENT AND TRADEMARK OFFICE

UNITED STATES DEPARTMENT OF COMMERCE
United States Patent and Trademark Office
Address: COMMISSIONER OF PATENTS AND TRADEMARKS
Washington, D.C. 20231
www.uspto.gov

APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
09/900,054	07/06/2001	Yi-Chuan Ding	JCLA6831	7810

7590
J.C. Patents, Inc.
4 Venture
Suite 250
Irvine, CA 92618

01/15/2003

EXAMINER

NGUYEN, KHIEM D

ART UNIT	PAPER NUMBER
----------	--------------

2823

DATE MAILED: 01/15/2003

Please find below and/or attached an Office communication concerning this application or proceeding.

Office Action Summary

Application No.

09/900,054

Applicant(s)

DING ET AL.

Examiner

Khiem D Nguyen

Art Unit

2823

-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address --

Period for Reply

A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE 3 MONTH(S) FROM THE MAILING DATE OF THIS COMMUNICATION.

- Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication.
- If the period for reply specified above is less than thirty (30) days, a reply within the statutory minimum of thirty (30) days will be considered timely.
- If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication.
- Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133).
- Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b).

Status

- 1) ☒ Responsive to communication(s) filed on 28 October 2002.
- 2a) ☒ This action is **FINAL**. 2b) ☐ This action is non-final.
- 3) ☐ Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under *Ex parte Quayle*, 1935 C.D. 11, 453 O.G. 213.

Disposition of Claims

- 4) ☒ Claim(s) 1-12 is/are pending in the application.
- 4a) Of the above claim(s) _____ is/are withdrawn from consideration.
- 5) ☐ Claim(s) _____ is/are allowed.
- 6) ☒ Claim(s) 1-12 is/are rejected.
- 7) ☐ Claim(s) _____ is/are objected to.
- 8) ☐ Claim(s) _____ are subject to restriction and/or election requirement.

Application Papers

- 9) ☐ The specification is objected to by the Examiner.
- 10) ☒ The drawing(s) filed on 06 July 2001 is/are: a) ☒ accepted or b) ☐ objected to by the Examiner.
- Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).
- 11) ☐ The proposed drawing correction filed on _____ is: a) ☐ approved b) ☐ disapproved by the Examiner.
- If approved, corrected drawings are required in reply to this Office action.
- 12) ☐ The oath or declaration is objected to by the Examiner.

Priority under 35 U.S.C. §§ 119 and 120

- 13) ☒ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).
- a) ☒ All b) ☐ Some * c) ☐ None of:
1. ☐ Certified copies of the priority documents have been received.
2. ☐ Certified copies of the priority documents have been received in Application No. _____.
3. ☐ Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)).
- * See the attached detailed Office action for a list of the certified copies not received.
- 14) ☐ Acknowledgment is made of a claim for domestic priority under 35 U.S.C. § 119(e) (to a provisional application).
- a) ☐ The translation of the foreign language provisional application has been received.
- 15) ☐ Acknowledgment is made of a claim for domestic priority under 35 U.S.C. §§ 120 and/or 121.

Attachment(s)

- 1) ☐ Notice of References Cited (PTO-892)
- 2) ☐ Notice of Draftsperson's Patent Drawing Review (PTO-948)
- 3) ☐ Information Disclosure Statement(s) (PTO-1449) Paper No(s) _____.
- 4) ☐ Interview Summary (PTO-413) Paper No(s). _____.
- 5) ☐ Notice of Informal Patent Application (PTO-152)
- 6) ☐ Other: _____.

DETAILED ACTION

Specification Objection is withdrawn

The objection to claim 1 is withdrawn in response to applicant's amendments.

New Grounds of Rejection

Claim Rejections - 35 USC § 103

1. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all

obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negated by the manner in which the invention was made.

2. Claims 1-6 are rejected under 35 U.S.C. 103(a) as being unpatentable over Egawa et al.

(U.S. Patent 6,376,278) in view of Belke, Jr. et al. (U.S. Patent 6,326,241) and Hung

(U.S. Patent 6,380,624).

Egawa teaches a flip chip packaging process comprising (See col. 4, line 9 to col. 8, line 9 and FIGS. 2(A)-9(A)):

providing a wafer 12 having a plurality of chips 18 formed thereon, wherein each chip has an active surface 18a (See FIG. 2A);

providing a plurality of individual substrates 28, wherein each substrate includes at least a package unit;

respectively mounting the substrates onto the wafer such that each package unit corresponds to each chip wherein two neighboring substrates are separated by a gap (See col. 4, lines 9-17 and FIG. 2B);

filling an underfill material 34 between the substrates and the wafer, wherein the underfill material being introduced through the gaps between the substrates and from the boundary of the wafer (See col. 4, lines 35-47 and FIG. 2C);

solidifying the underfill material (See col. 4, line 45); and

dicing the wafer and the substrates to form a plurality of individualized packages 66, each individualized package including one chip and one package unit wherein the surface of each package unit is equal to the active surface of the corresponding chip (See col. 7, lines 55-62).

Egawa fails to teach that each chip has an active surface provided with a plurality of bonding pads and each package unit having a plurality of contact pads wherein a gold bump is formed on each bonding pad and the contact pads are respectively connected to the corresponding bumps as recited in present claims 1 and 5.

Belke teaches a flip-chip 12 has an active surface provided with a plurality of bonding pads 14 and a substrate having a plurality of bonding pads 20 wherein a gold bump 16 is formed on each bonding pad of the flip-chip and the bonding pads of the substrate are respectively connected to the corresponding bumps. See col. 4, line 58 to col. 5, line 12 and FIGS. 1-2. It would have been obvious to one of ordinary skill in the art of making semiconductor devices to incorporate Belke's teaching into Egawa's method because doing so can provide the electrical inputs and outputs to the flip-chip 12. See col. 4, lines 63-66 and FIGS. 1-2.

Egawa fails to teach that each substrate includes a plurality of patterned conductive layers alternately laminated with a plurality of insulating layers wherein the

Art Unit: 2823

material of the insulating layer is FR-4, FR-5, bismaleimide triazine (BT), polyimide, or materials composite of epoxy and ceramic as recited in present claims 2-4.

Hung teaches a substrate 228 includes a plurality of patterned copper films (236a and 236b) alternately laminated with a plurality of insulating layers 230 wherein the material of the insulating layer is FR-4, FR-5 and bismaleimide triazine (BT). See col. 4, lines 6-20 and FIG. 4. It would have been obvious to one of ordinary skill in the art of making semiconductor devices to incorporate Hung's teaching into Egawa's method because doing so can make the production and the assembly of the memory module easier. See col. 1, lines 65-67.

3. Claims 7-12 are rejected under 35 U.S.C. 103(a) as being unpatentable over Egawa et al. (U.S. Patent 6,376,278) in view of Belke, Jr. et al. (U.S. Patent 6,326,241) and Hung (U.S. Patent 6,380,624).

Egawa teaches a flip chip packaging process comprising (See col. 7, line 2 to col. 8, line 9 and FIGS. 7-9(A)):

providing a wafer 12 having a plurality of chips 18 formed thereon, wherein each chip has an active surface 18a (See FIG. 2A);

providing a plurality of individual substrates 28, wherein each substrate includes at least a package unit ;

respectively mounting the substrates onto the wafer such that each package unit corresponds to one chip wherein two neighboring substrates are separated by a gap (See col. 4, lines 9-17 and FIG. 2B);

filling an underfill material 34 between the substrates and the wafer, wherein the underfill material being introduced through the gaps between the substrates and from the boundary of the wafer (See col. 4, lines 35-47 and FIG. 2C);

solidifying the underfill material (See col. 4, line 45); and

dicing the wafer and the substrates to form a plurality of individualized packages 66, each individualized package including one package unit and one chip wherein the surface of each package unit is equal to the active surface of the corresponding chip (See col. 7, lines 55-62).

Egawa fails to teach that each chip provided with a plurality of bonding pads and each package unit having a plurality of contact pads wherein a gold bump is formed on each contact pad and the bonding pads are respectively connected to the corresponding bumps as recited in present claims 7 and 11.

Belke teaches a flip-chip 12' has an active surface provided with a plurality of contact pads 20' and a substrate 18' having a plurality of bonding pads 14' wherein a gold bump 16' is formed on each bonding pad of the substrate and the contact pads of the flip-chip are respectively connected to the corresponding bumps. See col. 4, lines 66-67 and col. 6, lines 30-48 and FIGS. 2-3. It would have been obvious to one of ordinary skill in the art of making semiconductor devices to incorporate Belke's teaching into Egawa's method because doing so can provide the electrical inputs and outputs to the flip-chip 12. See col. 4, lines 63-66 and FIG. 3.

Egawa fails to teach that each substrate includes a plurality of patterned conductive layers alternately laminated with a plurality of insulating layers wherein the

Art Unit: 2823

material of the insulating layer is FR-4, FR-5, bismaleimide triazine (BT), polyimide, or materials composite of epoxy and ceramic as recited in present claims 8-10.

Hung teaches a substrate 228 includes a plurality of patterned copper films (236a and 236b) alternately laminated with a plurality of insulating layers 230 wherein the material of the insulating layer is FR-4, FR-5 and bismaleimide triazine (BT). See col. 4, lines 6-20 and FIG. 4. It would have been obvious to one of ordinary skill in the art of making semiconductor devices to incorporate Hung's teaching into Egawa's method because doing so can make the production and the assembly of the memory module easier. See col. 1, lines 65-67.

Response to Amendment

Responding to applicant's Arguments

Applicant's arguments with respect to claims 1-12 have been considered but are moot in view of the new ground(s) of rejection.

In response to applicant's argument that Egawa et al., Belke and Hung fail to teach or suggest that mounting a plurality of individual substrates onto the wafer which includes a plurality of the chips in a manner that two neighboring substrates are separated by a gap, filling an underfill material through the gaps between the substrates, and then dicing the wafer and the substrate, _____

_____ Egawa et al. disclose in (col. 4, lines 9-63 and FIGS. 2(A-C)) mounting a plurality of individual substrates 28 onto the wafer 12 using a bonding tool 30 which includes a plurality of the chips 18 in a manner that two neighboring substrates are separated by a gap (See col. 4, lines 9-17 and FIG. 2B), filling an underfill material 34 through the gaps

between the substrates using a resin dispenser 32 (See col. 4, lines 35-47 and FIG. 2C), and then dicing the wafer and the substrate to form a plurality of individualized packages (See col. 7, lines 55-62). Thus, the references teach all the claim limitations.

Conclusion

Applicant's amendment necessitated the new ground(s) of rejection presented in this Office action. Accordingly, **THIS ACTION IS MADE FINAL**. See MPEP § 706.07(a). Applicant is reminded of the extension of time policy as set forth in 37 CFR 1.136(a).

A shortened statutory period for reply to this final action is set to expire **THREE MONTHS** from the mailing date of this action. In the event a first reply is filed within **TWO MONTHS** of the mailing date of this final action and the advisory action is not mailed until after the end of the **THREE-MONTH** shortened statutory period, then the shortened statutory period will expire on the date the advisory action is mailed, and any extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of the advisory action. In no event, however, will the statutory period for reply expire later than **SIX MONTHS** from the date of this final action.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Khiem D Nguyen whose telephone number is (703) 306-0210. The examiner can normally be reached on Monday-Friday (8:00 AM - 5:00 PM).


If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Chaudhuri Olik can be reached on (703) 306-2794. The fax phone numbers

Art Unit: 2823

for the organization where this application or proceeding is assigned are (703) 746-9179 for regular communications and (703) 746-9179 for After Final communications.

Any inquiry of a general nature or relating to the status of this application or proceeding should be directed to the receptionist whose telephone number is (703) 308-0956.

K.N.
January 2, 2003


George Fourson
Primary Examiner
2823